# Characterization of micro- and nano-materials, Key aspect:
“Advanced methods for materials characterization”
12th – 16th September 2022, Cottbus, LG 1A, R. 304

<table>
<thead>
<tr>
<th>Time</th>
<th>Monday, 12/09/2022</th>
<th>Tuesday, 13/09/2022</th>
<th>Wednesday, 14/09/2022</th>
<th>Thursday, 15/09/2022</th>
<th>Friday, 16/09/2022</th>
</tr>
</thead>
</table>
| 9:00-10:30   | Lecture Ehrenfried Zschech  
BTU/deepXscan GmbH  
X-ray tomography | Lecture Carlos Morales  
BTU  
Quantitative x-ray photoelectron spectroscopy | Lecture Vedran Vonk  
DESY Hamburg  
(Nano) x-ray diffraction | Lecture Joachim Wollschläger  
Uni Osnabrück  
Electron diffraction | Lecture Michal Mazur  
Wroclaw University of Science and Technology  
Transmission and scanning electron microscopy |
| 10:30-11:00  | Coffee Break        |                      |                       |                      |                     |
| 11:00-12:30  | Lecture Malgorzata Kot  
BTU  
Atomic layer deposition | Lecture David Starr  
Helmholtz-Zentrum Berlin  
Near-ambient pressure photoelectron spectroscopy | Lecture Thomas Schmidt  
Uni Bremen  
Dynamical x-ray diffraction and x-ray standing waves | Lecture Thomas Schmidt  
Fritz-Haber-Institut Berlin  
Low-energy and photoemission electron microscopy | Lecture Niklas Nilius  
Uni Oldenburg  
Scanning tunneling microscopy and spectroscopy |
| 12:30-14:00  | Lunch Break         |                      |                       |                      |                     |
| 14:00-15:00  | Tutorial Paul Plate  
Sentech  
In-situ ellipsometry | Experiments:  
X-ray photoelectron spectroscopy | Conference Outing/BBQ | Experiments:  
Electron diffraction and photoemission electron microscopy |                     |
| 15:30-18:00  | Experiments:  
Atomic layer deposition |                      |                       |                      |                     |